

| 作者: Photo-Walk
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| 10页 | 20 January 2007. Lenses for x-rays are notoriously tricky to manufacture because they rely on nanometre-scale features. For this reason, physicists developing x-ray microscopes have been keen to adopt "lensless" designs that measure diffraction when x-rays are passed through samples. But until this principle has worked well for periodic structures such as crystals, methods for non-periodic structures such as biological materials have been ineffective. In creating lenses for x-

ray microscopes, data from just a single diffraction measurement are taken, which must then be subjected to an algorithm that gradually zeroes in on a "solution" or image after many thousands of rays. At the University of Sheffield, however, John Rodenburg and colleagues have used a sophisticated technique dating from 1989 called "synchrography" that enables many overlapping diffraction measurements to be taken at once. This makes it easier to identify the positions of the periodic features in the sample. The team's work has now been published online in *Nature*. The researchers say that the new technique could be applied to other types of x-ray microscope, such as those used for medical CT scans. "We can get as good an image as the best optical microscope in the world," he said.

